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May 2002
 Revised May 2002

74LVT322245 • 74LVTH322245

Low Voltage 32-Bit Transceiver with 3-STATE Outputs and 25Ω Series Resistors in A Port Outputs

General Description

The LVT322245 and LVTH322245 contain thirty-two non-inverting bidirectional buffers with 3-STATE outputs and are intended for bus oriented applications. The device is byte controlled. Each byte has separate control inputs which can be shorted together for full 32-bit operation. The T/R inputs determine the direction of data flow through the device. The OE inputs disable both the A and B ports by placing them in a high impedance state.

The LVT322245 and LVTH322245 are designed with equivalent 25Ω series resistance in both the HIGH and LOW states on the A Port outputs. This design reduces line noise in applications such as memory address drivers, clock drivers, and bus transceivers/transmitters.

The LVTH322245 data inputs include bushold, eliminating the need for external pull-up resistors to hold unused inputs.

These non-inverting transceivers are designed for low-voltage (3.3V) V_{CC} applications, but with the capability to provide a TTL interface to a 5V environment. The LVT322245 and LVTH322245 are fabricated with an advanced BiCMOS technology to achieve high speed operation similar to 5V ABT while maintaining a low power dissipation.

Features

- Input and output interface capability to systems at 5V V_{CC}
- Bushold data inputs eliminate the need for external pull-up resistors to hold unused inputs (74LVTH322245)
- Also available without bushold feature (74LVT322245)
- Live insertion/extraction permitted
- Power Up/Power Down high impedance provides glitch-free bus loading
- A Port outputs include equivalent series resistance of 25Ω making external termination resistors unnecessary and reducing overshoot and undershoot
- A Port outputs source/sink ±12 mA
 B Port outputs source/sink -32 mA/+64 mA
- ESD performance:
 Human-body model > 2000V
 Machine model > 200V
 Charged-device model > 1000V
- Packaged in plastic Fine-Pitch Ball Grid Array (FBGA)

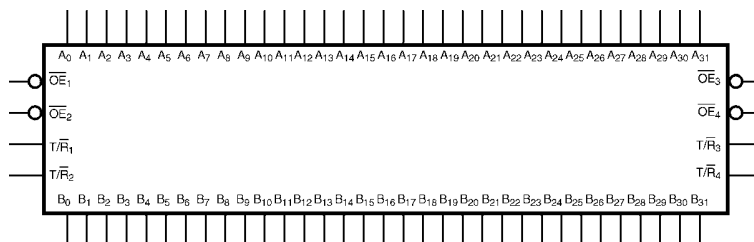
Ordering Code:

Order Number	Package Number	Package Description
74LVT322245G (Note 1) (Note 2)	BGA96A (Preliminary)	96-Ball Fine-Pitch Ball Grid Array (FBGA), JEDEC MO-205, 5.5mm Wide
74LVTH322245G (Note 1) (Note 2)	BGA96A	96-Ball Fine-Pitch Ball Grid Array (FBGA), JEDEC MO-205, 5.5mm Wide

Note 1: Ordering code "G" indicates TRAYS.

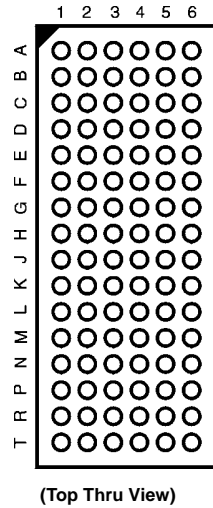
Note 2: Devices also available in TAPE and REEL. Specify by appending the suffix letter "X" to the ordering code.

Logic Symbol



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Connection Diagram



FBGA Pin Descriptions

Pin Names	Description
\overline{OE}_n	Output Enable Input (Active LOW)
T/\overline{R}_n	Transmit/Receive Input
A_0 - A_{31}	Side A Inputs/3-STATE Outputs
B_0 - B_{31}	Side B Inputs/3-STATE Outputs

Pin Assignments for FBGA

	1	2	3	4	5	6
A	B_1	B_0	T/\overline{R}_1	\overline{OE}_1	A_0	A_1
B	B_3	B_2	GND	GND	A_2	A_3
C	B_5	B_4	V_{CC1}	V_{CC1}	A_4	A_5
D	B_7	B_6	GND	GND	A_6	A_7
E	B_9	B_8	GND	GND	A_8	A_9
F	B_{11}	B_{10}	V_{CC1}	V_{CC1}	A_{10}	A_{11}
G	B_{13}	B_{12}	GND	GND	A_{12}	A_{13}
H	B_{14}	B_{15}	T/\overline{R}_2	\overline{OE}_2	A_{15}	A_{14}
J	B_{17}	B_{16}	T/\overline{R}_3	\overline{OE}_3	A_{16}	A_{17}
K	B_{19}	B_{18}	GND	GND	A_{18}	A_{19}
L	B_{21}	B_{20}	V_{CC2}	V_{CC2}	A_{20}	A_{21}
M	B_{23}	B_{22}	GND	GND	A_{22}	A_{23}
N	B_{25}	B_{24}	GND	GND	A_{24}	A_{25}
P	B_{27}	B_{26}	V_{CC2}	V_{CC2}	A_{26}	A_{27}
R	B_{29}	B_{28}	GND	GND	A_{28}	A_{29}
T	B_{30}	B_{31}	T/\overline{R}_4	\overline{OE}_4	A_{31}	A_{30}

Truth Tables

Inputs		Outputs
\overline{OE}_1	T/\overline{R}_1	
L	L	Bus B_0 - B_7 Data to Bus A_0 - A_7
L	H	Bus A_0 - A_7 Data to Bus B_0 - B_7
H	X	HIGH-Z State on A_0 - A_7 , B_0 - B_7

Inputs		Outputs
\overline{OE}_2	T/\overline{R}_2	
L	L	Bus B_8 - B_{15} Data to Bus A_8 - A_{15}
L	H	Bus A_8 - A_{15} Data to Bus B_8 - B_{15}
H	X	HIGH-Z State on A_8 - A_{15} , B_8 - B_{15}

H = HIGH Voltage Level
 L = LOW Voltage Level
 X = Immaterial
 Z = High Impedance

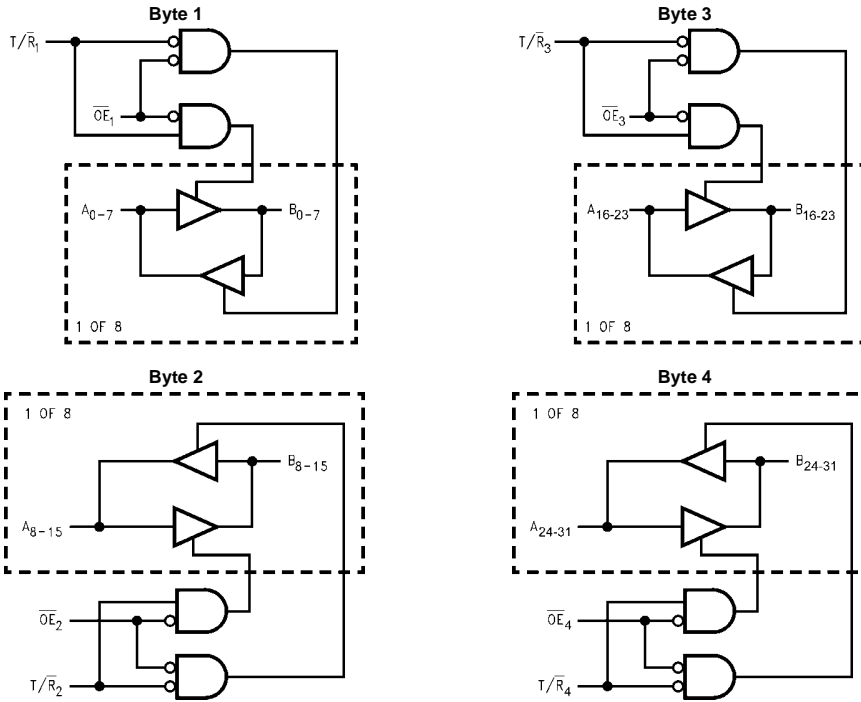
Inputs		Outputs
\overline{OE}_3	T/\overline{R}_3	
L	L	Bus B_{16} - B_{23} Data to Bus A_{16} - A_{23}
L	H	Bus A_{16} - A_{23} Data to Bus B_{16} - B_{23}
H	X	HIGH-Z State on A_{16} - A_{23} , B_{16} - B_{23}

Inputs		Outputs
\overline{OE}_4	T/\overline{R}_4	
L	L	Bus B_{24} - B_{31} Data to Bus A_{24} - A_{31}
L	H	Bus A_{24} - A_{31} Data to Bus B_{24} - B_{31}
H	X	HIGH-Z State on A_{24} - A_{31} , B_{24} - B_{31}

Functional Description

The LVT322245 and LVTH322245 contain thirty-two non-inverting bidirectional buffers with 3-STATE outputs. The device is byte controlled with each byte functioning identically, but independent of the other. The control pins can be shorted together to obtain 16-bit or full 32-bit operation.

Logic Diagrams



V_{CC1} is associated with Bytes 1 and 2.

V_{CC2} is associated with Bytes 3 and 4.

Note: Please note that these diagrams are provided only for the understanding of logic operations and should not be used to estimate propagation delays.

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Absolute Maximum Ratings (Note 3)						
Symbol	Parameter	Value	Conditions		Units	
V _{CC}	Supply Voltage	-0.5 to +4.6			V	
V _I	DC Input Voltage	-0.5 to +7.0			V	
V _O	Output Voltage	-0.5 to +7.0	Output in 3-STATE		V	
		-0.5 to +7.0	Output in HIGH or LOW State (Note 4)			
I _{IK}	DC Input Diode Current	-50	V _I < GND		mA	
I _{OK}	DC Output Diode Current	-50	V _O < GND		mA	
I _O	DC Output Current	64	V _O > V _{CC} Output at HIGH State		mA	
		128	V _O > V _{CC} Output at LOW State			
I _{CC}	DC Supply Current per Supply Pin	±64			mA	
I _{GND}	DC Ground Current per Ground Pin	±128			mA	
T _{STG}	Storage Temperature	-65 to +150			°C	

Recommended Operating Conditions						
Symbol	Parameter	Min	Max	Units		
V _{CC}	Supply Voltage	2.7	3.6	V		
V _I	Input Voltage	0	5.5	V		
I _{OH}	HIGH Level Output Current			B Port	-32	mA
				A Port	-12	
I _{OL}	LOW Level Output Current			B Port	64	mA
				A Port	12	
T _A	Free Air Operating Temperature	-40	+85	°C		
Δt/ΔV	Input Edge Rate, V _{IN} = 0.8V-2.0V, V _{CC} = 3.0V	0	10	ns/V		

Note 3: Absolute Maximum continuous ratings are those values beyond which damage to the device may occur. Exposure to these conditions or conditions beyond those indicated may adversely affect device reliability. Functional operation under absolute maximum rated conditions is not implied.

Note 4: I_O Absolute Maximum Rating must be observed.

DC Electrical Characteristics							
Symbol	Parameter	V _{CC} (V)	T _A = -40°C to +85°C		Units	Conditions	
			Min	Max			
V _{IK}	Input Clamp Diode Voltage	2.7		-1.2	V	I _I = -18 mA	
V _{IH}	Input HIGH Voltage	2.7-3.6	2.0		V	V _O ≤ 0.1V or V _O ≥ V _{CC} - 0.1V	
V _{IL}	Input LOW Voltage	2.7-3.6		0.8	V		
V _{OH}	Output HIGH Voltage	A Port	3.0	2.0	V	I _{OH} = -12 mA	
			2.7-3.6	V _{CC} - 0.2	V	I _{OH} = -100 μA	
		B Port	2.7	2.4	V	I _{OH} = -8 mA	
			3.0	2.0	V	I _{OH} = -32 mA	
V _{OL}	Output LOW Voltage	A Port	3.0	0.8	V	I _{OL} = 12 mA	
			2.7	0.2	V	I _{OL} = 100 μA	
		B Port	2.7	0.5	V	I _{OL} = 24 mA	
			3.0	0.4		I _{OL} = 16 mA	
			3.0	0.5		I _{OL} = 32 mA	
			3.0	0.55		I _{OL} = 64 mA	
I _{I(HOLD)} (Note 5)	Bushold Input Minimum Drive	3.0	75		μA	V _I = 0.8V	
			-75			V _I = 2.0V	
I _{I(OD)} (Note 5)	Bushold Input Over-Drive Current to Change State	3.0	500		μA	(Note 6)	
			-500			(Note 7)	
I _I	Input Current	3.6		10	μA	V _I = 5.5V	
			Control Pins			±1	V _I = 0V or V _{CC}
			Data Pins			-5	V _I = 0V
I _{OFF}	Power Off Leakage Current	0		±100	μA	0V ≤ V _I or V _O ≤ 5.5V	

DC Electrical Characteristics (Continued)							
Symbol	Parameter	V _{CC} (V)	T _A = -40°C to +85°C		Units	Conditions	
			Min	Max			
I _{PU/PD}	Power Up/Down 3-STATE Current	0-1.5V		±100	μA	V _O = 0.5V to 3.0V V _I = GND to V _{CC}	
I _{OZL}	3-STATE Output Leakage Current	3.6		-5	μA	V _O = 0.5V	
I _{OZL} (Note 5)	3-STATE Output Leakage Current	3.6		-5	μA	V _O = 0.0V	
I _{OZH}	3-STATE Output Leakage Current	3.6		5	μA	V _O = 3.0V	
I _{OZH} (Note 5)	3-STATE Output Leakage Current	3.6		5	μA	V _O = 3.6V	
I _{OZH+}	3-STATE Output Leakage Current	3.6		10	μA	V _{CC} < V _O ≤ 5.5V	
I _{CCH}	Power Supply Current V _{CC1} or V _{CC2}	3.6		0.19	mA	Outputs HIGH	
I _{CCL}	Power Supply Current V _{CC1} or V _{CC2}	3.6		5	mA	Outputs LOW	
I _{CCZ}	Power Supply Current V _{CC1} or V _{CC2}	3.6		0.19	mA	Outputs Disabled	
I _{CCZ+}	Power Supply Current V _{CC1} or V _{CC2}	3.6		0.19	mA	V _{CC} ≤ V _O ≤ 5.5V, Outputs Disabled	
ΔI _{CC}	Increase in Power Supply Current (Note 8) V _{CC1} or V _{CC2}	3.6		0.2	mA	One Input at V _{CC} - 0.6V Other Inputs at V _{CC} or GND	
<p>Note 5: Applies to bushold versions only (74LVTH322245).</p> <p>Note 6: An external driver must source at least the specified current to switch from LOW-to-HIGH.</p> <p>Note 7: An external driver must sink at least the specified current to switch from HIGH-to-LOW.</p> <p>Note 8: This is the increase in supply current for each input that is at the specified voltage level rather than V_{CC} or GND.</p>							
Dynamic Switching Characteristics (Note 9)							
Symbol	Parameter	V _{CC} (V)	T _A = 25°C			Units	Conditions C _L = 50 pF R _L = 500Ω
			Min	Typ	Max		
V _{OLP}	Quiet Output Maximum Dynamic V _{OL}	3.3		0.8		V	(Note 10)
V _{OLV}	Quiet Output Minimum Dynamic V _{OL}	3.3		-0.8		V	(Note 10)
<p>Note 9: Characterized in SSOP package. Guaranteed parameter, but not tested.</p> <p>Note 10: Max number of outputs defined as (n). n-1 data inputs are driven 0V to 3V. Output under test held LOW.</p>							
AC Electrical Characteristics							
Symbol	Parameter	T _A = -40°C to +85°C C _L = 50 pF, R _L = 500Ω				Units	
		V _{CC} = 3.3V ± 0.3V		V _{CC} = 2.7V			
		Min	Max	Min	Max		
t _{PLH}	Propagation Delay Data to A Port Output	1.0	4.0	1.0	4.6	ns	
t _{PHL}		1.0	3.7	1.0	4.1		
t _{PLH}	Propagation Delay Data to B Port Output	1.0	3.5	1.0	3.9	ns	
t _{PHL}		1.0	3.5	1.0	3.9		
t _{PZH}	Output Enable Time for A Port Output	1.0	5.3	1.0	6.3	ns	
t _{PZL}		1.0	5.6	1.0	7.2		
t _{PZH}	Output Enable Time for B Port Output	1.0	4.6	1.0	5.4	ns	
t _{PZL}		1.0	5.3	1.0	6.9		
t _{PHZ}	Output Disable Time for A Port Output	1.5	5.6	1.5	6.3	ns	
t _{PLZ}		1.5	5.5	1.5	5.5		
t _{PHZ}	Output Disable Time for B Port Output	1.5	5.4	1.5	6.1	ns	
t _{PLZ}		1.5	5.1	1.5	5.4		
Capacitance (Note 11)							
Symbol	Parameter	Conditions		Typical	Units		
C _{IN}	Input Capacitance	V _{CC} = 0V, V _I = 0V or V _{CC}		4	pF		
C _{I/O}	Input/Output Capacitance	V _{CC} = 3.0V, V _O = 0V or V _{CC}		8	pF		
Note 11: Capacitance is measured at frequency f = 1 MHz, per MIL-STD-883, Method 3012.							

74LVTH322245 • 74LVTH322245 Low Voltage 32-Bit Transceiver with 3-STATE Outputs and 25Ω Series Resistors in A Port Outputs

Physical Dimensions

inches (millimeters) unless otherwise noted

\oplus	0.15(M)	C	A	B
	0.08(M)	C		

Top View

Bottom View

SEATING PLANE

NOTES:

- THIS PACKAGE CONFORMS TO JEDEC MO-205
- ALL DIMENSIONS IN MILLIMETERS
- LAND PATTERN RECOMMENDATION: NSMD (Non Solder Mask Defined)
.35MM DIA PADS WITH A SOLDERMASK OPENING OF .45MM CONCENTRIC TO PADS
- DRAWING CONFORMS TO ASME Y14.5M-1994

BGA96revE

**96-Ball Fine-Pitch Ball Grid Array (FBGA), JEDEC MO-205, 5.5mm Wide
Package Number BGA96A**

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